

CHAPTER 18:

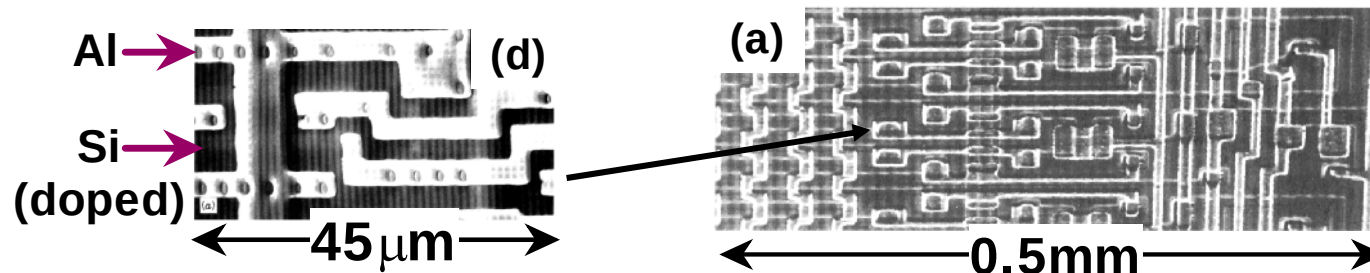
ELECTRICAL PROPERTIES

ISSUES TO ADDRESS...

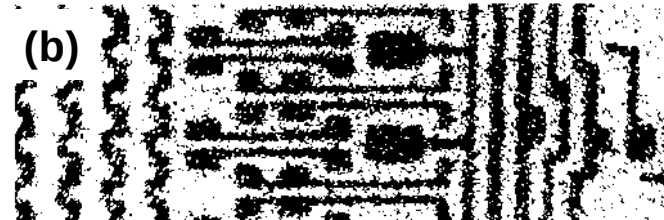
- **How are electrical conductance and resistance characterized?**
- **What are the physical phenomena that distinguish conductors, semiconductors, and insulators?**
- **For metals, how is conductivity affected by imperfections, T , and deformation?**
- **For semiconductors, how is conductivity affected by impurities (doping) and T ?**

VIEW OF AN INTEGRATED CIRCUIT

- Scanning electron microscope images of an IC:



- A dot map showing location of Si (a semiconductor):
--Si shows up as light regions.



- A dot map showing location of Al (a conductor):
--Al shows up as light regions.

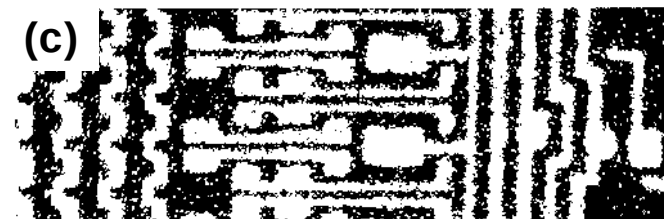
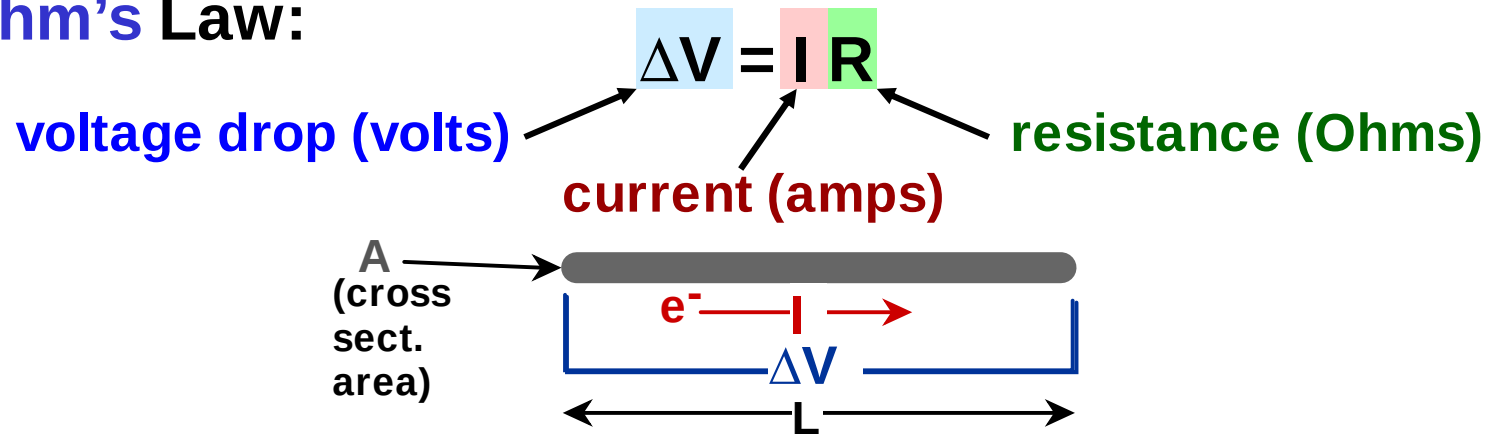


Fig. (d) from Fig. 18.25, *Callister 6e*. (Fig. 18.25 is courtesy Nick Gonzales, National Semiconductor Corp., West Jordan, UT.)

Fig. (a), (b), (c) from Fig. 18.0, *Callister 6e*.

ELECTRICAL CONDUCTION

- **Ohm's Law:**



- **Resistivity, ρ and Conductivity, σ :**
--geometry-independent forms of Ohm's Law

Diagram illustrating the relationship between electric field intensity, current density, resistivity, and conductivity:

Equation: $\frac{\Delta V}{L} = \frac{I}{A} \rho$

Labels and arrows:

- $\frac{\Delta V}{L}$ (E: electric field intensity) points to the blue box containing $\frac{\Delta V}{L}$.
- $\frac{I}{A}$ (J: current density) points to the red box containing $\frac{I}{A}$.
- ρ (resistivity in Ohm-m) points to the green box containing ρ .

Below the equation, the relationship between conductivity and resistivity is shown:

Equation: $\sigma = \frac{1}{\rho}$

Label and arrow:

- σ (conductivity) points to the purple box containing σ .

- **Resistance:** $R = \frac{\rho L}{A} = \frac{L}{A\sigma}$

CONDUCTIVITY: COMPARISON

- Room T values (Ohm-m)⁻¹

METALS

conductors

Silver

6.8×10^7

Copper

6.0×10^7

Iron

1.0×10^7

CERAMICS

Soda-lime glass

10^{-10}

Concrete

10^{-9}

Aluminum oxide

$<10^{-13}$

SEMICONDUCTORS

Silicon

4×10^{-4}

Germanium

2×10^0

GaAs

10^{-6}

semiconductors

POLYMERS

Polystyrene

$<10^{-14}$

Polyethylene

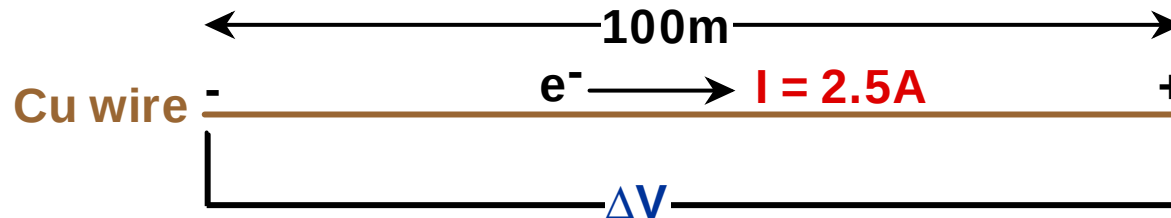
10^{-15} - 10^{-17}

insulators

Selected values from Tables 18.1, 18.2, and 18.3, *Callister 6e*.

EX: CONDUCTIVITY PROBLEM

- Question 18.2, p. 649, *Callister 6e*:



What is the minimum diameter (D) of the wire so that $\Delta V < 1.5V$?

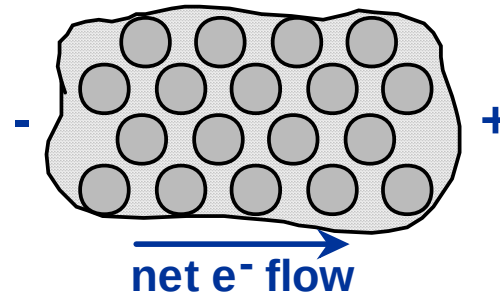
$$R = \frac{L}{A\sigma} = \frac{\Delta V}{I}$$

Diagram illustrating the formula for resistance R in terms of length L , cross-sectional area A , and conductivity σ . The length L is 100m. The cross-sectional area A is given by $\frac{\pi D^2}{4}$. The conductivity σ is $6.07 \times 10^7 \text{ (Ohm-m)}^{-1}$. The voltage difference ΔV is less than 1.5V. The current I is 2.5A.

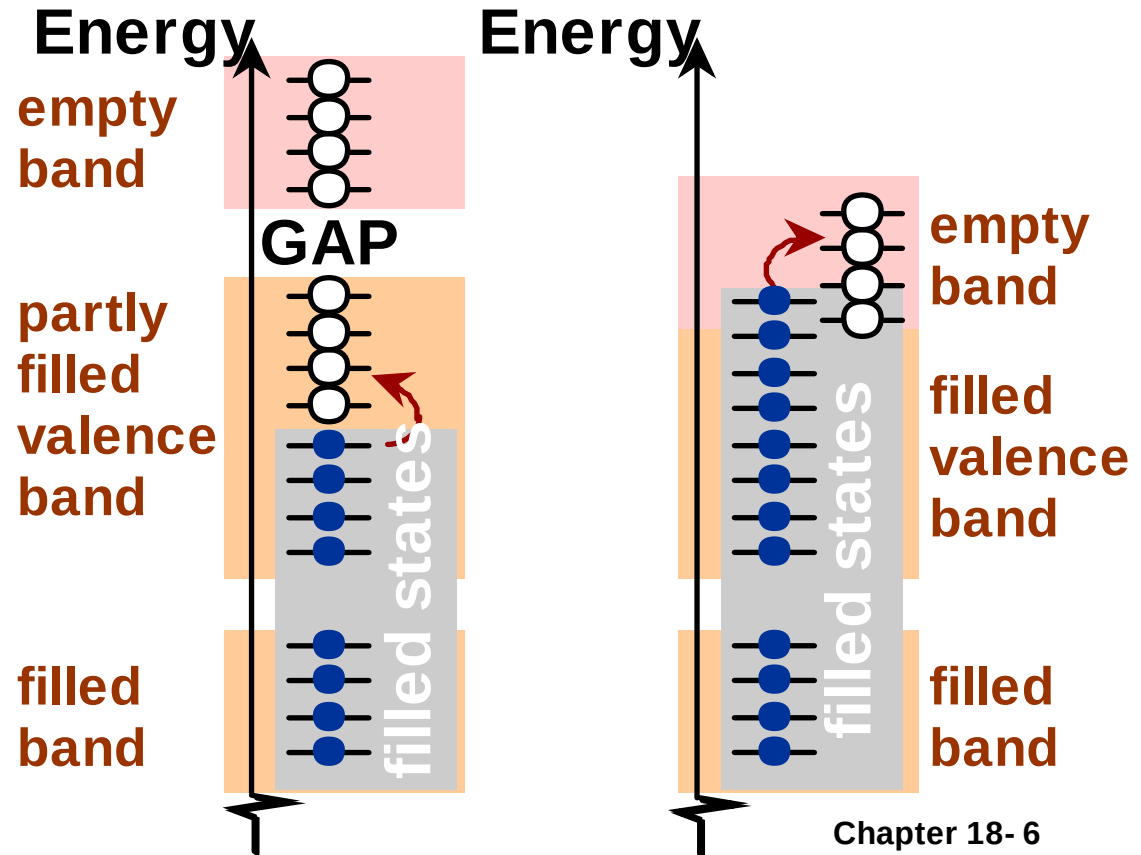
Solve to get $D > 1.88 \text{ mm}$

CONDUCTION & ELECTRON TRANSPORT

- Metals:
 - Thermal energy puts many electrons into a higher energy state.



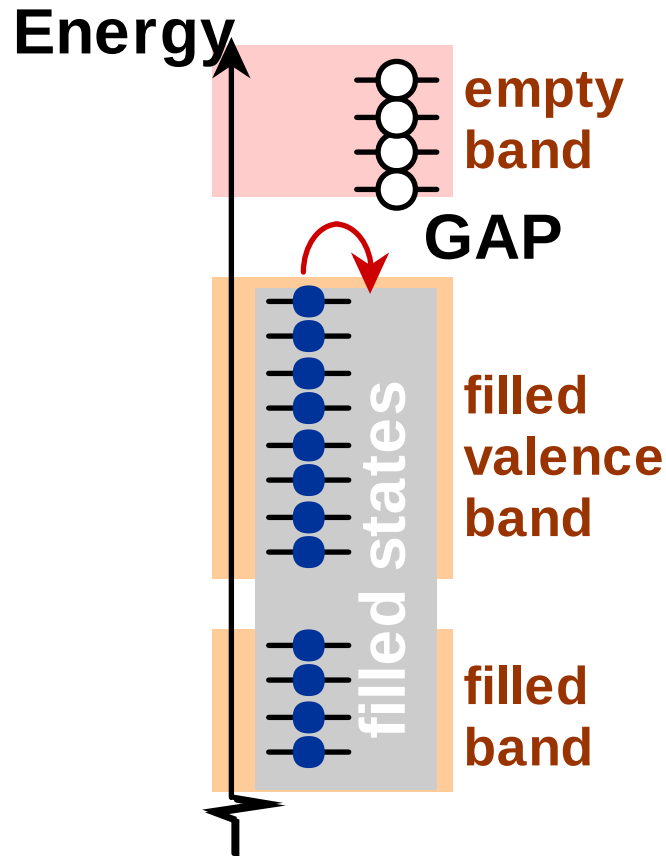
- Energy States:
 - the cases below for metals show that nearby energy states are accessible by thermal fluctuations.



ENERGY STATES: INSULATORS AND SEMICONDUCTORS

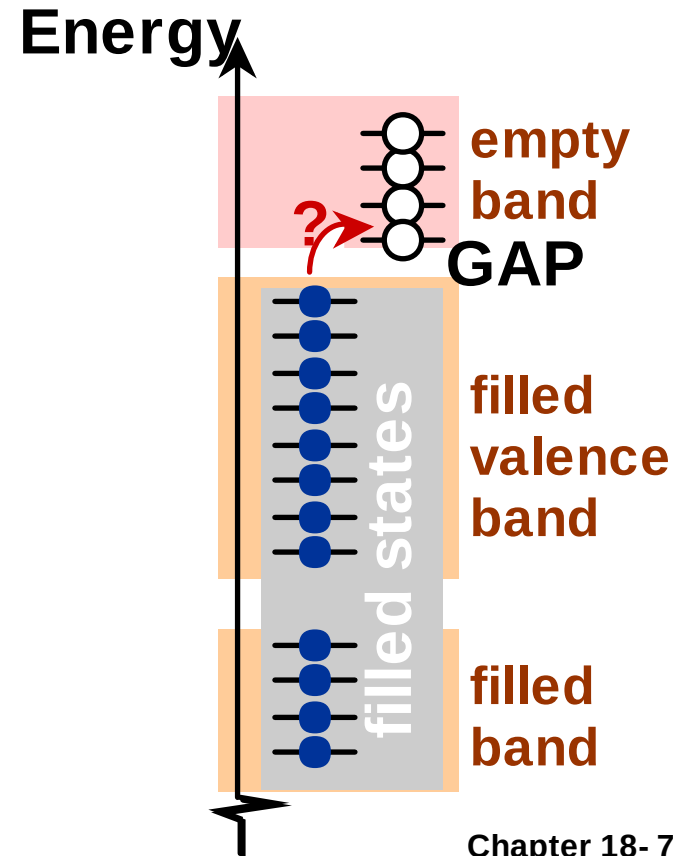
- Insulators:

- Higher energy states not accessible due to gap.



- Semiconductors:

- Higher energy states separated by a smaller gap.

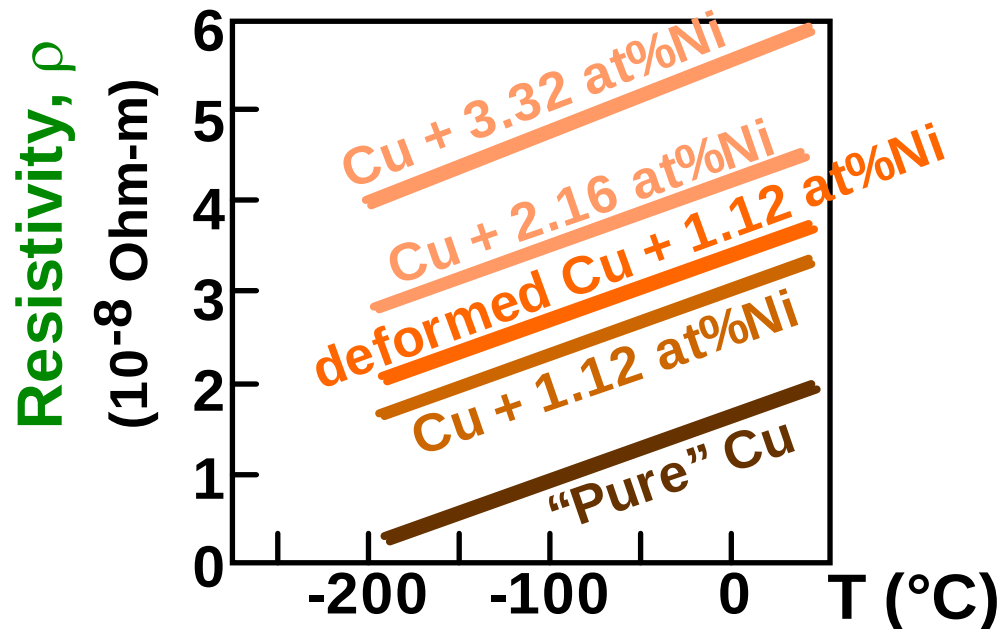


METALS: RESISTIVITY VS T, IMPURITIES

- Imperfections increase resistivity

- grain boundaries
- dislocations
- impurity atoms
- vacancies

These act to scatter electrons so that they take a less direct path.



- Resistivity increases with:
 - temperature
 - wt% impurity
 - %CW

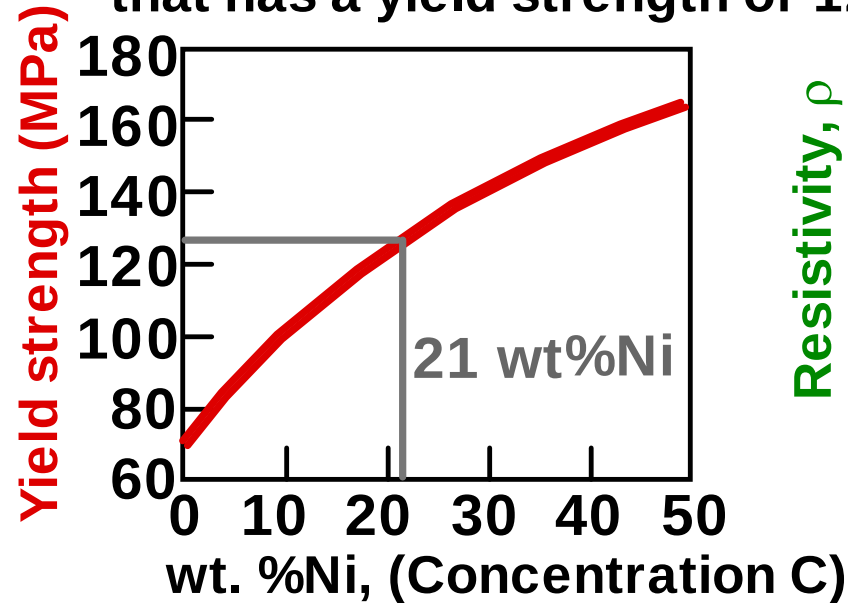
$$\rho = \rho_{\text{thermal}} + \rho_{\text{thermal}} + \rho_{\text{def}}$$

Adapted from Fig. 18.8, *Callister 6e*. (Fig. 18.8 adapted from J.O. Linde, *Ann. Physik* 5, p. 219 (1932); and C.A. Wert and R.M. Thomson, *Physics of Solids*, 2nd ed., McGraw-Hill Book Company, New York, 1970.)

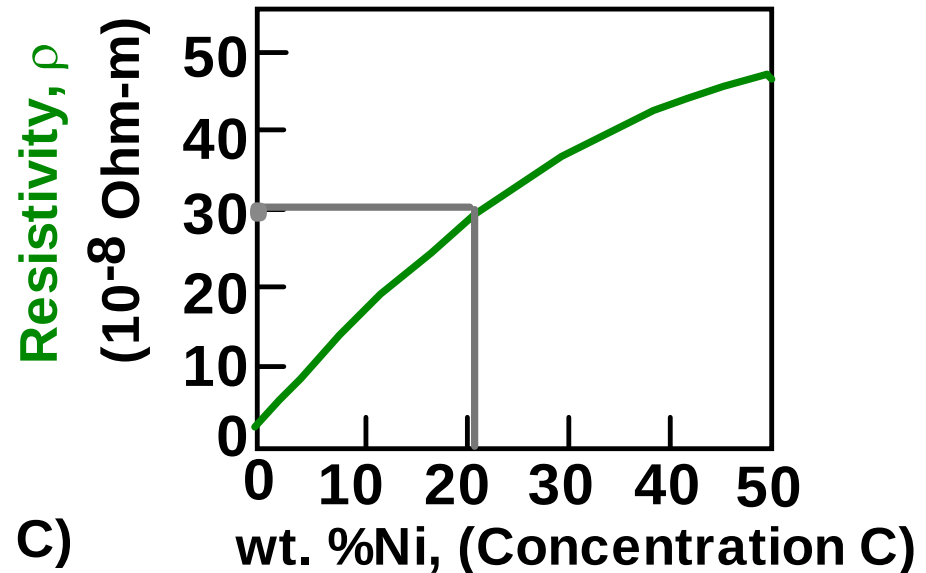
EX: ESTIMATING CONDUCTIVITY

- Question:

--Estimate the electrical conductivity of a Cu-Ni alloy that has a yield strength of 125MPa.



Adapted from Fig. 7.14(b), Callister 6e.



Adapted from Fig. 18.9, Callister 6e.

$$\rho = 30 \times 10^{-8} \text{ Ohm} - \text{m}$$

$$\sigma = \frac{1}{\rho} = 3.3 \times 10^6 (\text{Ohm} - \text{m})^{-1}$$

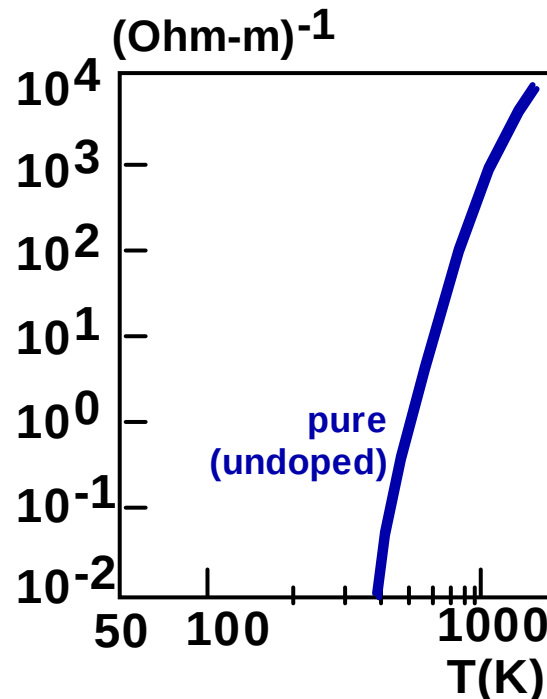
PURE SEMICONDUCTORS: CONDUCTIVITY VS T

- Data for **Pure Silicon**:

- σ increases with T

- opposite to metals

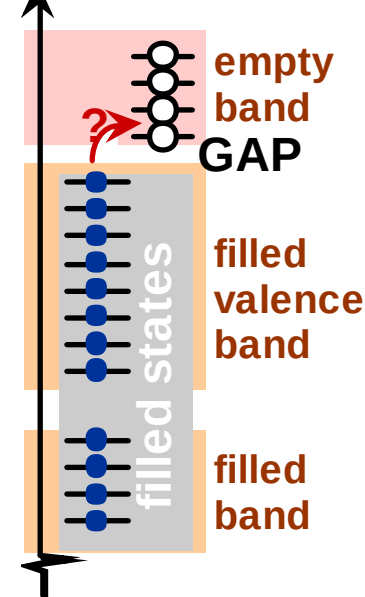
electrical conductivity, σ



Adapted from Fig. 19.15, *Callister 5e*. (Fig. 19.15 adapted from G.L. Pearson and J. Bardeen, *Phys. Rev.* 75, p. 865, 1949.)

$$\sigma_{\text{undoped}} \propto e^{-E_{\text{gap}} / kT}$$

Energy



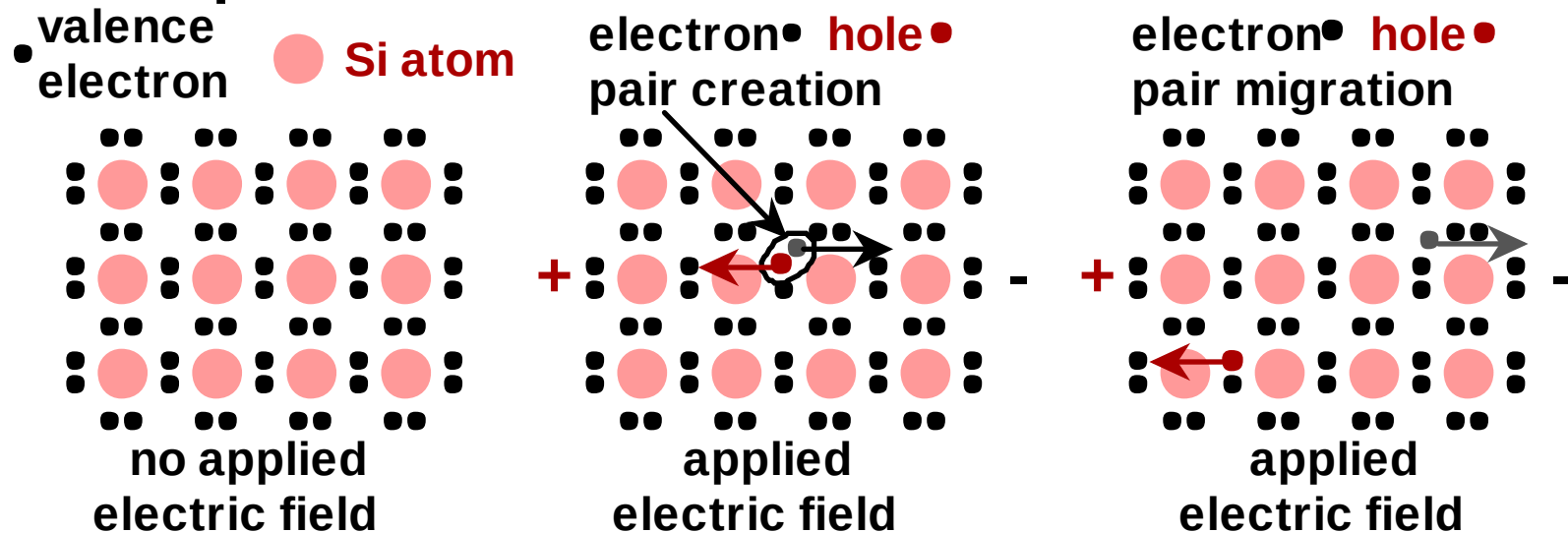
electrons
can cross
gap at
higher T

material	band gap (eV)
Si	1.11
Ge	0.67
GaP	2.25
CdS	2.40

Selected values from
Table 18.2, *Callister 6e*.

CONDUCTION IN TERMS OF ELECTRON AND HOLE MIGRATION

- Concept of electrons and holes:



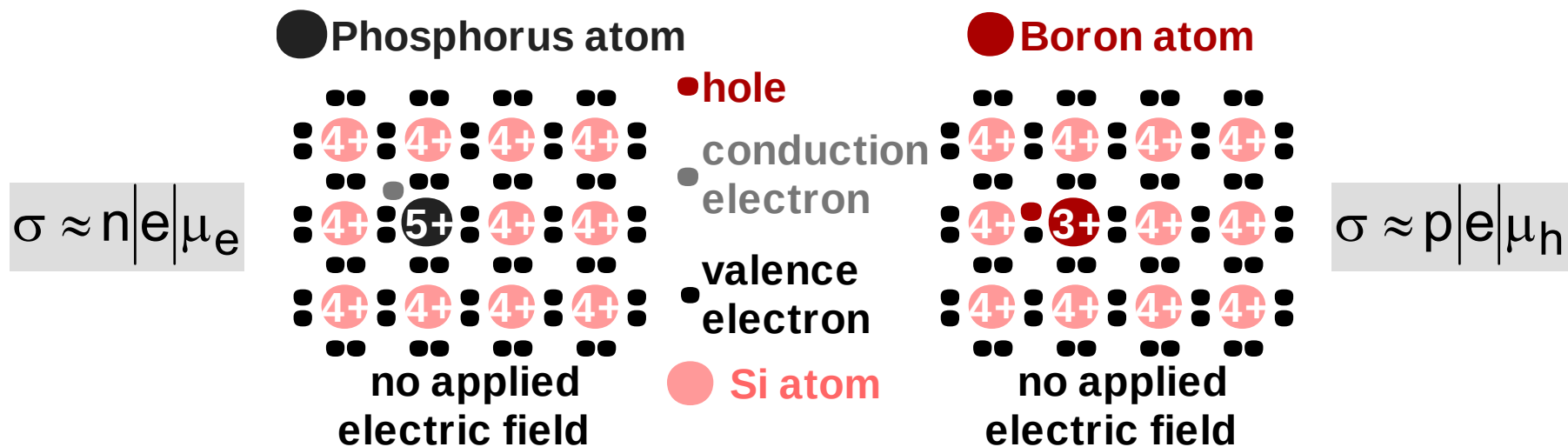
Adapted from Fig. 18.10,
Callister 6e.

- Electrical Conductivity given by:

$$\sigma = \underset{\substack{\uparrow \\ \text{\# electrons/m}^3}}{n} |e| \underset{\substack{\uparrow \\ \text{electron mobility}}}{\mu_e} + \underset{\substack{\downarrow \\ \text{\# holes/m}^3}}{p} |e| \underset{\substack{\leftarrow \\ \text{hole mobility}}}{\mu_h}$$

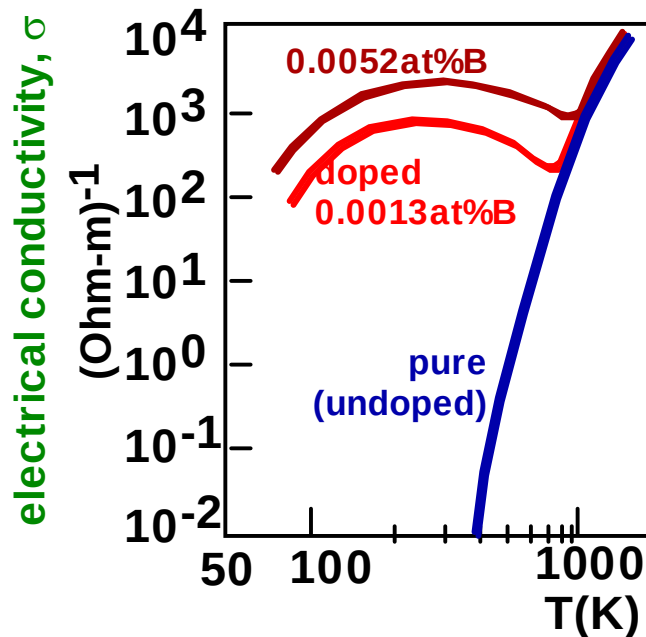
INTRINSIC VS EXTRINSIC CONDUCTION

- **Intrinsic:**
 - # electrons = # holes ($n = p$)
 - case for pure Si
- **Extrinsic:**
 - $n \neq p$
 - occurs when impurities are added with a different # valence electrons than the host (e.g., Si atoms)
- **N-type Extrinsic:** ($n \gg p$) • **P-type Extrinsic:** ($p \gg n$)

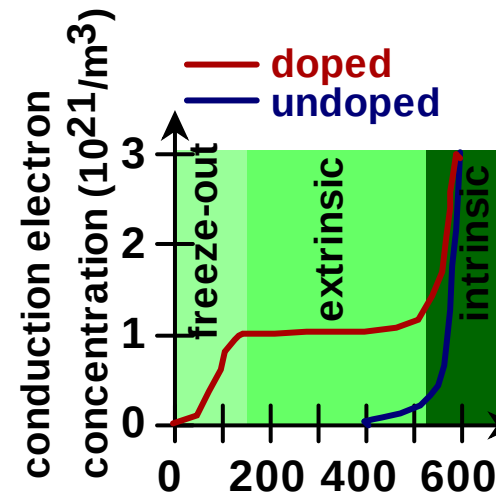


DOPED SEMICON: CONDUCTIVITY VS T

- Data for **Doped Silicon**:
 - σ increases doping
 - reason: imperfection sites lower the activation energy to produce mobile electrons.
- Comparison: **intrinsic** vs **extrinsic** conduction...
 - extrinsic doping level: $10^{21}/\text{m}^3$ of a n-type donor impurity (such as P).
 - for $T < 100\text{K}$: "freeze-out" thermal energy insufficient to excite electrons.
 - for $150\text{K} < T < 450\text{K}$: "extrinsic"
 - for $T \gg 450\text{K}$: "intrinsic"



Adapted from Fig. 19.15, *Callister 5e*. (Fig. 19.15 adapted from G.L. Pearson and J. Bardeen, *Phys. Rev.* 75, p. 865, 1949.)

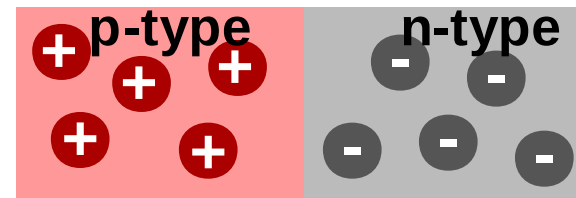


Adapted from Fig. 18.16, *Callister 6e*. (Fig. 18.16 from S.M. Sze, *Semiconductor Devices, Physics, and Technology*, Bell Telephone Laboratories, Inc., 1985.)

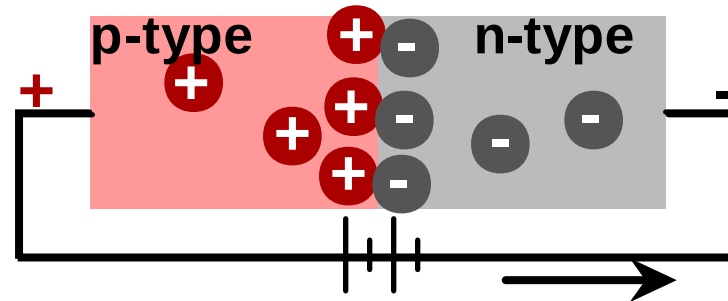
P-N RECTIFYING JUNCTION

- Allows flow of electrons in one direction only (e.g., useful to convert alternating current to direct current).
- Processing: diffuse P into one side of a B-doped crystal.
- Results:

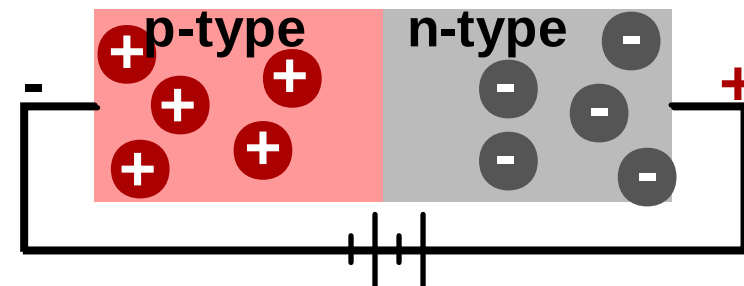
--No applied potential:
no net current flow.



--Forward bias: carrier
flow through p-type and
n-type regions; holes and
electrons recombine at
p-n junction; current flows.



--Reverse bias: carrier
flow away from p-n junction;
carrier conc. greatly reduced
at junction; little current flow.



SUMMARY

- Electrical **conductivity** and **resistivity** are:
 - material parameters.
 - geometry independent.
- Electrical **resistance** is:
 - a geometry and material dependent parameter.
- Conductors, semiconductors, and insulators...
 - different in whether there are accessible energy states for conductance electrons.
- For metals, conductivity is increased by
 - reducing deformation
 - reducing imperfections
 - decreasing temperature.
- For pure semiconductors, conductivity is increased by
 - increasing temperature
 - doping (e.g., adding B to Si (p-type) or P to Si (n-type)).